

**Notice of References Cited**

Application/Control No.

10/774,590

Applicant(s)/Patent Under  
Reexamination  
NONAKA ET AL.

Examiner

DAVID P. RASHID

Art Unit

2624

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,594,311	07-2003	Pearlstein, Larry	375/240.01
*	B	US-5,991,503	11-1999	Miyasaka et al.	386/111
*	C	US-2001/0033737	10-2001	Honjo, Masahiro	386/52
*	D	US-6,181,743	01-2001	Bailleul, Nicolas	375/240
*	E	US-2002/0059643	05-2002	Kitamura et al.	725/136
*	F	US-2002/0067768	06-2002	Hurst, Robert N.	375/240.03
*	G	US-6,415,055	07-2002	Kato, Motoki	382/236
*	H	US-2002/0114397	08-2002	TODO et al.	375/240.29
*	I	US-2002/0136310	09-2002	Saunders et al.	375/240.25
*	J	US-2002/0181595	12-2002	OBATA et al.	375/240.25
*	K	US-2002/0186769	12-2002	O'Brien, Royal	375/240.12
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	V					
	W					
	X					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.